Editorial

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Following the 22nd *International Mixed-Signal Testing Workshop* (IMSTW 2017), held in Thessaloniki, Greece during July 4–6, 2017, we issued a call for papers for this special issue titled Analog, Mixed-Signal and Radio Frequency Testing (AMSRFT), under the guest editorship of Professor Ke Huang and Professor Manuel Barragan. Subsequently, all received submissions went through the journal's peer review process to select twelve articles appearing here.

The papers in this issue are grouped in four categories, namely, Accurate Signal Generation and Measurement, Hardware Security, Alternate Test and its BIST Implementation, and Reliability Analysis for State-of-the-Art Devices. I make a few observations that indicate the trends in the field. First, about half of the twelve papers are on testing of radio frequency devices, showing the prevailing majority in-

terest. Second, there are two papers dealing with hardware security, which is an emerging trend. Finally, the last paper in this issue is on reliability of MEMS sensors realized using 3D printing, a technology we hope to see more of in the future.

We are thankful to Professors Huang and Barragan for their effort that made this issue possible. Their Guest Editorial introduces the content.

Just when this issue gets out, IMSTW 2018, the 23rd workshop in the series, should be getting underway. However, there is a change. Starting this year, IMSTW will become part of the *IEEE International On-Line Test Symposium* (IOLTS). The combined event, named the 24th *IEEE International Symposium on On-Line Testing and Robust System Design*, will take place at Costa Brava, Spain during July 2–4, 2018.

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